

3 HIGH SIDE AND 3 LOW SIDE DRIVER

Features

- Floating channel designed for bootstrap operation
- Fully operational to +600V
- Tolerant to negative transient voltage
- dV/dt immune
- Gate drive supply range from 10 to 20V
- Undervoltage lockout for all channels
- Over-current shutdown turns off all six drivers
- Independent 3 high side & 3 low side drivers
- Matched propagation delay for all channels
- 2.5V logic compatible
- Outputs out of phase with inputs

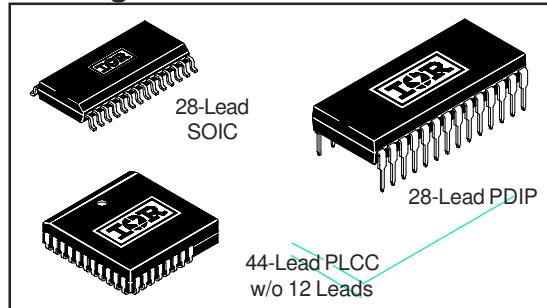
Description

The IR2131(J)(S) is a high voltage, high speed power MOSFET and IGBT driver with three independent high and low side referenced output channels. Proprietary HVIC technology enables ruggedized monolithic construction. Logic inputs are compatible with CMOS or LSTTL outputs, down to 2.5V logic. A current trip function which terminates all six outputs can be derived from an external current sense resistor. A shutdown input is provided for a customized shutdown function. An open drain FAULT signal is provided to indicate that any of the shutdowns has occurred. The output drivers feature a high pulse current buffer stage designed for minimum driver cross-conduction. Propagation delays are matched to simplify use in high frequency applications. The floating channels can be used to drive N-channel power MOSFETs or IGBTs in the high side configuration which operate up to 600 volts.

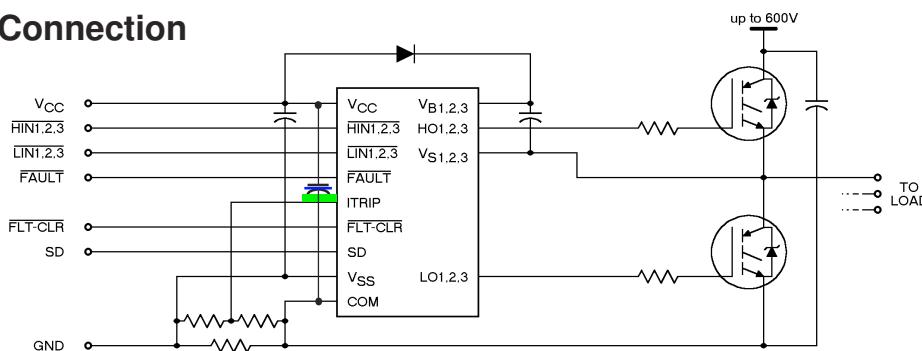
Product Summary

V_{OFFSET}	600V max.
I_O+/-	160 mA / 360 mA
V_{OUT}	10 - 20V
ton/off (typ.)	1.3 & 0.6 µs
Deadtime (typ.)	700 ns

Packages



Typical Connection



(Refer to Lead Assignments for correct pin configuration). This/These diagram(s) show electrical connections only.
Please refer to our Application Notes and DesignTips for proper circuit board layout.

Absolute Maximum Ratings

Absolute Maximum Ratings indicate sustained limits beyond which damage to the device may occur. All voltage parameters are absolute voltages referenced to COM. The Thermal Resistance and Power Dissipation ratings are measured under board mounted and still air conditions. Additional Information is shown in Figures 7 through 10.

Symbol	Definition	Min.	Max.	Units
$V_{B1,2,3}$	High Side Floating Supply Voltage	-0.3	625	V
$V_{S1,2,3}$	High Side Floating Offset Voltage	$V_{B1,2,3} - 25$	$V_{B1,2,3} + 0.3$	
$V_{HO1,2,3}$	High Side Floating Output Voltage	$V_{S1,2,3} - 0.3$	$V_{B1,2,3} + 0.3$	
V_{CC}	Low Side and Logic Fixed Supply Voltage	-0.3	25	
V_{SS}	Logic Ground	$V_{CC} - 25$	$V_{CC} + 0.3$	
$V_{LO1,2,3}$	Low Side Output Voltage	-0.3	$V_{CC} + 0.3$	
V_{IN}	Logic Input Voltage ($HIN1,2,3, LIN1,2,3, FLT-CLR, SD \& ITRIP$)	$V_{SS} - 0.3$	($V_{SS} + 15$) or ($V_{CC} + 0.3$) whichever is lower	
V_{FLT}	\overline{FAULT} Output Voltage	$V_{SS} - 0.3$	$V_{CC} + 0.3$	
dV_S/dt	Allowable Offset Supply Voltage Transient	—	50	V/ns
P_D	Package Power Dissipation @ $T_A \leq +25^\circ C$	(28 Lead DIP)	—	W
		(28 Lead SOIC)	—	
		(44 Lead PLCC)	—	
R_{thJA}	Thermal Resistance, Junction to Ambient	(28 Lead DIP)	—	$^\circ C/W$
		(28 Lead SOIC)	—	
		(44 Lead PLCC)	—	
T_J	Junction Temperature	—	150	$^\circ C$
T_S	Storage Temperature	-55	150	
T_L	Lead Temperature (Soldering, 10 seconds)	—	300	

Recommended Operating Conditions

The Input/Output logic timing diagram is shown in Figure 1. For proper operation the device should be used within the recommended conditions. All voltage parameters are absolute voltages referenced to COM. The V_S offset rating is tested with all supplies biased at 15V differential.

Symbol	Definition	Min.	Max.	Units
$V_{B1,2,3}$	High Side Floating Supply Voltage	$V_{S1,2,3} + 10$	$V_{S1,2,3} + 20$	V
$V_{S1,2,3}$	High Side Floating Offset Voltage	Note 1	600	
$V_{HO1,2,3}$	High Side Floating Output Voltage	$V_{S1,2,3}$	$V_{B1,2,3}$	
V_{CC}	Low Side and Logic Fixed Supply Voltage	10	20	
V_{SS}	Logic Ground	-5	5	
$V_{LO1,2,3}$	Low Side Output Voltage	0	V_{CC}	
V_{IN}	Logic Input Voltage ($HIN1,2,3, LIN1,2,3, FLT-CLR, SD \& ITRIP$)	V_{SS}	$V_{SS} + 5$	
V_{FLT}	\overline{FAULT} Output Voltage	V_{SS}	V_{CC}	
T_A	Ambient Temperature	-40	125	$^\circ C$

Note 1: Logic operational for V_S of -5V to +600V. Logic state held for V_S of -5V to $-V_{BS}$. (Please refer to the Design Tip DT97-3 for more details).

Note 2: All input pins, CA- and CAO pins are internally clamped with a 5.2V zener diode.

Dynamic Electrical Characteristics

V_{BIAS} (V_{CC} , $V_{BS1,2,3}$) = 15V, $V_{S1,2,3}$ = V_{SS} = COM, C_L = 1000 pF and T_A = 25°C unless otherwise specified. The dynamic electrical characteristics are defined in Figures 4 through 5.

Symbol	Parameter Definition	Value			Units	Test Conditions
		Min.	Typ.	Max.		
t_{on}	Turn-On Propagation Delay	0.6	1.3	2.0	μs	$V_{IN} = 0 \& 5V$ $V_{S1,2,3} = 0 \text{ to } 600V$
t_{off}	Turn-Off Propagation Delay	0.2	0.6	1.0		
t_r	Turn-On Rise Time	—	80	150		
t_f	Turn-Off Fall Time	—	40	100		
t_{trip}	ITRIP to Output Shutdown Propagation Delay	400	700	1000		
t_{bl}	ITRIP Blanking Time	—	400	—		
t_{fit}	ITRIP to FAULT Indication Delay	400	700	1000		
$t_{fit,in}$	Input Filter Time (All Six Inputs)	—	310	—		
t_{fitclr}	FLT-CLR to FAULT Clear Time	400	800	1200		
t_{sd}	SD to Output Shutdown Propagation Delay	400	700	1000		
DT	Deadtime	400	700	1200		

NOTE: For high side PWM, HIN pulse width must be $\geq 1.5\mu s$

Static Electrical Characteristics

V_{BIAS} (V_{CC} , $V_{BS1,2,3}$) = 15V, $V_{S1,2,3}$ = V_{SS} = COM and T_A = 25°C unless otherwise specified. The V_{IN} , V_{TH} and I_{IN} parameters are referenced to V_{SS} and are applicable to all six logic input leads: HIN1,2,3 & LIN1,2,3. The V_O and I_O parameters are referenced to COM and $V_{S1,2,3}$ and are applicable to the respective output leads: HO1,2,3 or LO1,2,3.

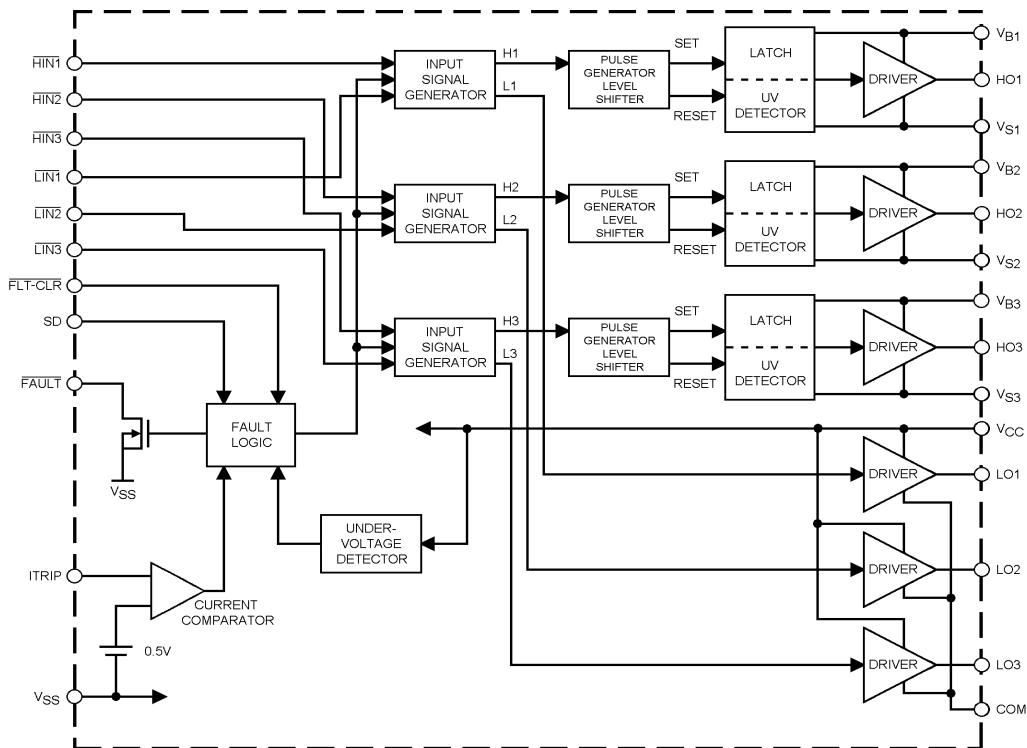
Symbol	Parameter Definition	Value			Units	Test Conditions
		Min.	Typ.	Max.		
V_{IH}	Logic "0" Input Voltage (OUT = LO)	2.2	—	—	V	$V_{IN} = 0V, I_O = 0A$ $V_{IN} = 5V, I_O = 0A$
V_{IL}	Logic "1" Input Voltage (OUT = HI)	—	—	0.8		
$V_{FCLR,IH}$	Logic "0" Fault Clear Input Voltage	2.2	—	—		
$V_{FCLR,IL}$	Logic "1" Fault Clear Input Voltage	—	—	0.8		
$V_{SD,TH+}$	Shutdown Input Positive Going Threshold	1.2	1.8	2.1		
$V_{SD,TH-}$	Shutdown Input Negative Going Threshold	0.9	1.5	1.8		
$V_{IT,TH+}$	ITRIP Input Positive Going Threshold	250	485	600		
$V_{IT,TH-}$	ITRIP Input Negative Going Threshold	200	400	550		
V_{OH}	High Level Output Voltage, V_{BIAS} - V_O	—	—	100		
V_{OL}	Low Level Output Voltage, V_O	—	—	100		
I_{LK}	Offset Supply Leakage Current	—	—	50	μA	$V_B = V_S = 600V$ $V_{IN} = 0V \text{ or } 5V$ $V_{IN} = 0V \text{ or } 5V$
I_{QBS}	Quiescent V_{BS} Supply Current	—	30	100		
I_{QCC}	Quiescent V_{CC} Supply Current	—	3.0	4.5		
I_{IN+}	Logic "1" Input Bias Current (OUT = HI)	—	190	300		
I_{IN-}	Logic "0" Input Bias Current (OUT = LO)	—	50	100		
I_{ITRIP+}	"High" ITRIP Bias Current	—	75	150		
I_{ITRIP-}	"Low" ITRIP Bias Current	—	—	100		
I_{FCLR+}	Logic "1" Fault Clear Bias Current	—	125	250		
I_{FCLR-}	Logic "0" Fault Clear Bias Current	—	75	150		
I_{SD+}	Logic "1" Shutdown Bias Current	—	75	150		
I_{SD-}	Logic "0" Shutdown Bias Current	—	—	100	nA	SD = 5V
						SD = 0V

Static Electrical Characteristics -- Continued

V_{BIAS} ($V_{CC}, V_{BS1,2,3} = 15V$, $V_{S1,2,3} = V_{SS} = COM$ and $T_A = 25^\circ C$ unless otherwise specified. The V_{IN} , V_{TH} and I_{IN} parameters are referenced to V_{SS} and are applicable to all six logic input leads: $HIN1,2,3 & LIN1,2,3$. The V_O and I_O parameters are referenced to COM and $V_{S1,2,3}$ and are applicable to the respective output leads: $HO1,2,3$ or $LO1,2,3$.

Symbol	Parameter Definition	Min.	Typ.	Max.	Units	Test Conditions
V_{BSUV+}	V_{BS} Supply Undervoltage Positive Going Threshold	8.2	8.7	9.2	V	
V_{BSUV-}	V_{BS} Supply Undervoltage Negative Going Threshold	7.8	8.3	8.8		
V_{CCUV+}	V_{CC} Supply Undervoltage Positive Going Threshold	8.2	8.7	9.2		
V_{CCUV-}	V_{CC} Supply Undervoltage Negative Going Threshold	7.8	8.3	8.8		
$R_{on,FLT}$	FAULT Low On-Resistance	—	55	75	Ω	
I_{O+}	Output High Short Circuit Pulsed Current	160	250	—	mA	$V_O = 0V, V_{IN} = 0V$ $PW \leq 10 \mu s$
I_{O-}	Output Low Short Circuit Pulsed Current	360	500	—		$V_O = 15V, V_{IN} = 5V$ $PW \leq 10 \mu s$

Functional Block Diagram



Lead Definitions

Lead Symbol	Description
HIN1,2,3	Logic inputs for high side gate driver outputs (HO1,2,3), out of phase
LIN1,2,3	Logic inputs for low side gate driver output (LO1,2,3), out of phase
FLT - CLR	Logic input for fault clear
SD	Logic input for shutdown
FAULT	Indicates over-current or undervoltage lockout (low side) has occurred, negative logic
VCC	Low side and logic fixed supply
ITRIP	Input for over-current shutdown
VSS	Logic ground
VB1,2,3	High side floating supplies
HO1,2,3	High side gate drive outputs
VS1,2,3	High side floating supply returns
LO1,2,3	Low side gate drive outputs
COM	Low side return

Lead Assignments

The diagram illustrates the lead assignments for three packages based on the IR2131 part number:

- 28 Lead DIP:** Shows pins 1 through 14. Pin 1 is VCC, 2 is HIN1, 3 is HIN2, 4 is HIN3, 5 is LIN1, 6 is LIN2, 7 is LIN3, 8 is FAULT, 9 is ITRIP, 10 is FLT-CLR, 11 is SD, 12 is VSS, 13 is COM, 14 is LO3. Pin 28 is VB1, 27 is HO1, 26 is VS1, 25 is HIN3, 24 is VB2, 23 is HO2, 22 is VS2, 21 is LIN3, 20 is VB3, 19 is HO3, 18 is VS3, 17 is VSS, 16 is LO1, and 15 is LO2.
- 44 Lead PLCC w/o 12 Leads:** Shows pins 1 through 44. Pins 1 through 17 are identical to the DIP layout. Pins 18 through 25 are floating pins (GND). Pins 26 through 33 are floating pins (VDD). Pins 34 through 41 are floating pins (VDD). Pins 42 and 43 are floating pins (GND). Pin 44 is VS1.
- 28 Lead SOIC (Wide Body):** Shows pins 1 through 14. Pin 1 is VCC, 2 is HIN1, 3 is HIN2, 4 is HIN3, 5 is LIN1, 6 is LIN2, 7 is LIN3, 8 is FAULT, 9 is ITRIP, 10 is FLT-CLR, 11 is SD, 12 is VSS, 13 is COM, 14 is LO3. Pin 28 is VB1, 27 is HO1, 26 is VS1, 25 is HIN3, 24 is VB2, 23 is HO2, 22 is VS2, 21 is LIN3, 20 is VB3, 19 is HO3, 18 is VS3, 17 is VSS, 16 is LO1, and 15 is LO2.

IR2131	IR2131J	IR2131S
Part Number		

IR2131(J)(S)

International
IR Rectifier

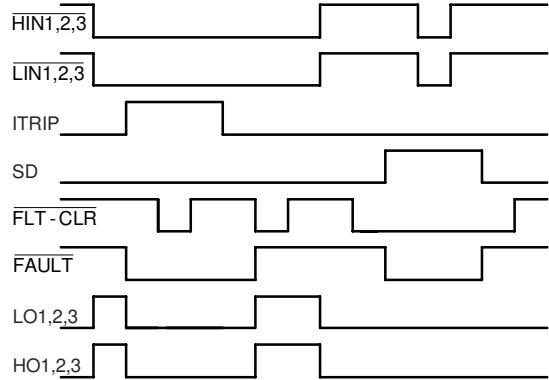


Figure 1. Input/Output Timing Diagram

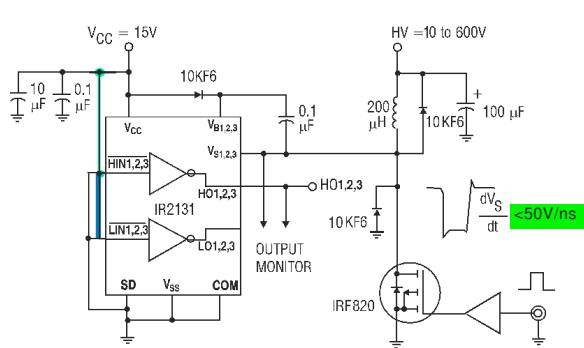


Figure 2. Floating Supply Voltage Transient Test Circuit

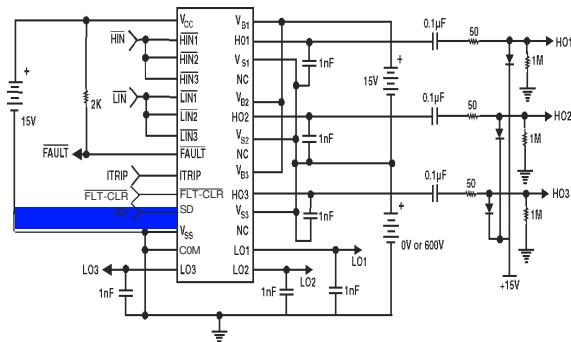


Figure 3. Switching Time Test Circuit

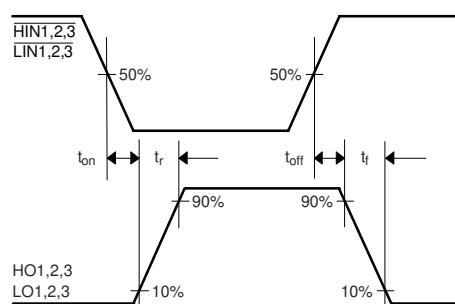


Figure 4. Switching Time Waveform Definitions

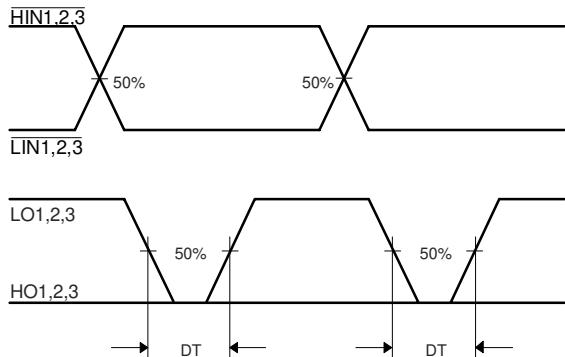


Figure 5. Deadtime Waveform Definitions

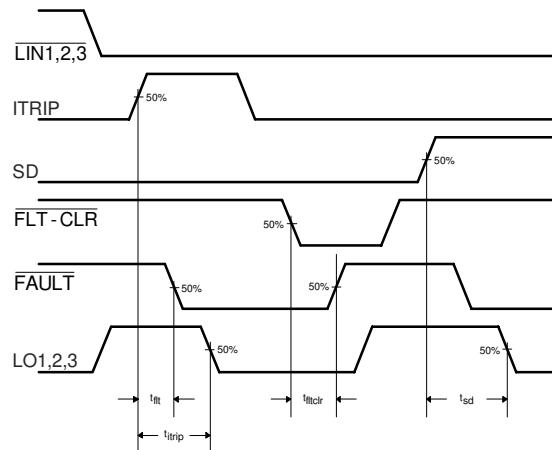


Figure 6. Shutdown Waveform Definitions

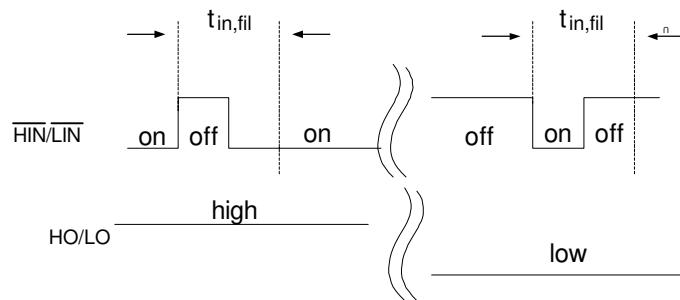


Figure 6.5 Input Filter Function

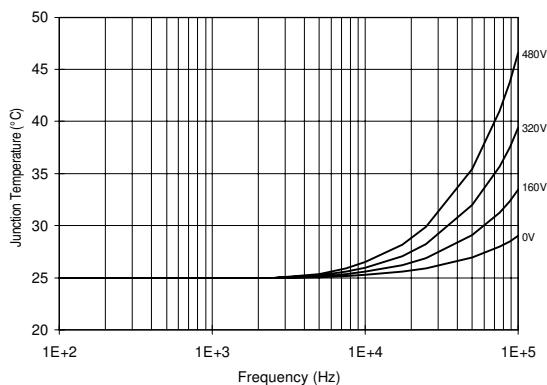


Figure 7. IR2131 T_J vs. Frequency (IRF820)
 $R_{GATE} = 33\Omega$, $V_{CC} = 15V$

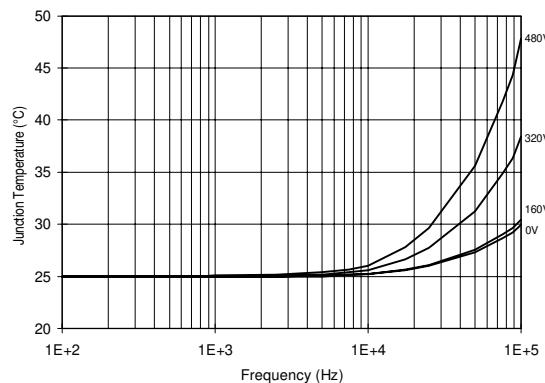


Figure 8. IR2131 T_J vs. Frequency (IRF830)
 $R_{GATE} = 20\Omega$, $V_{CC} = 15V$

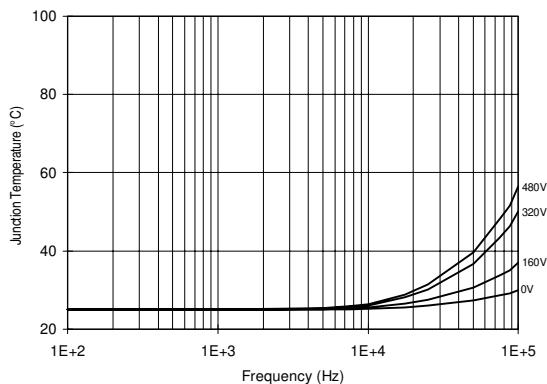


Figure 9. IR2131 T_J vs. Frequency (IRF840)
 $R_{GATE} = 15\Omega$, $V_{CC} = 15V$

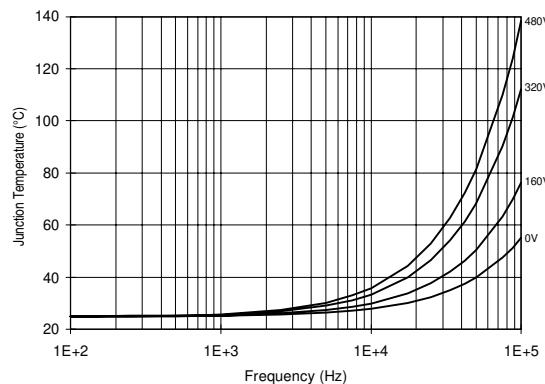
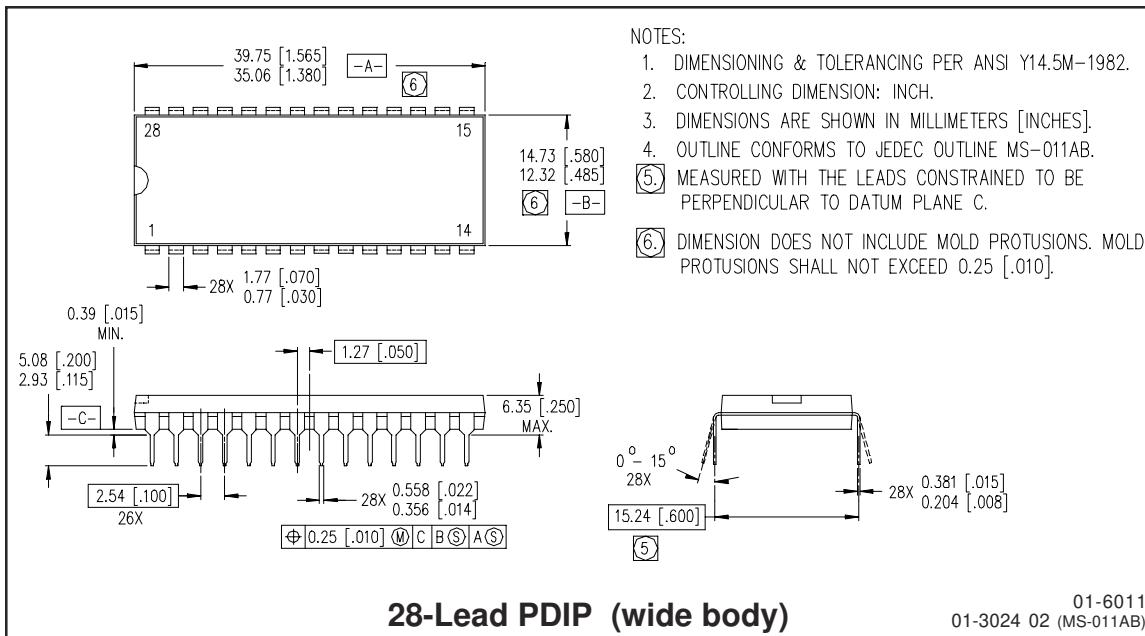
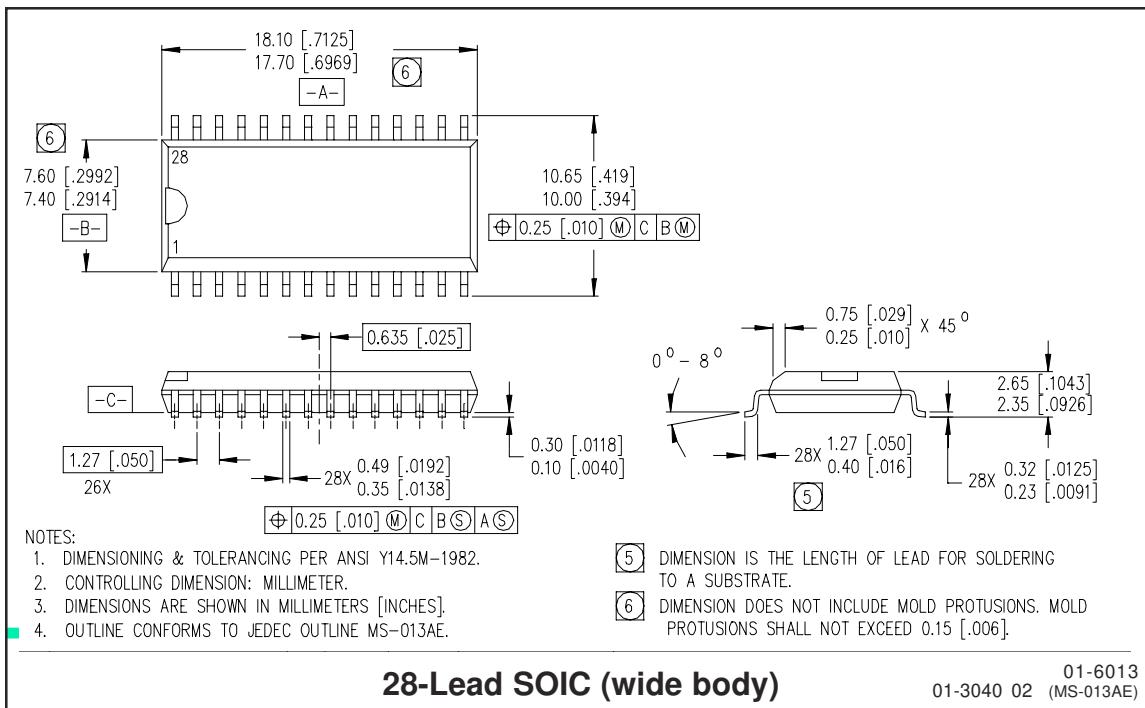


Figure 10. IR2131 T_J vs. Frequency (IRF450)
 $R_{GATE} = 10\Omega$, $V_{CC} = 15V$

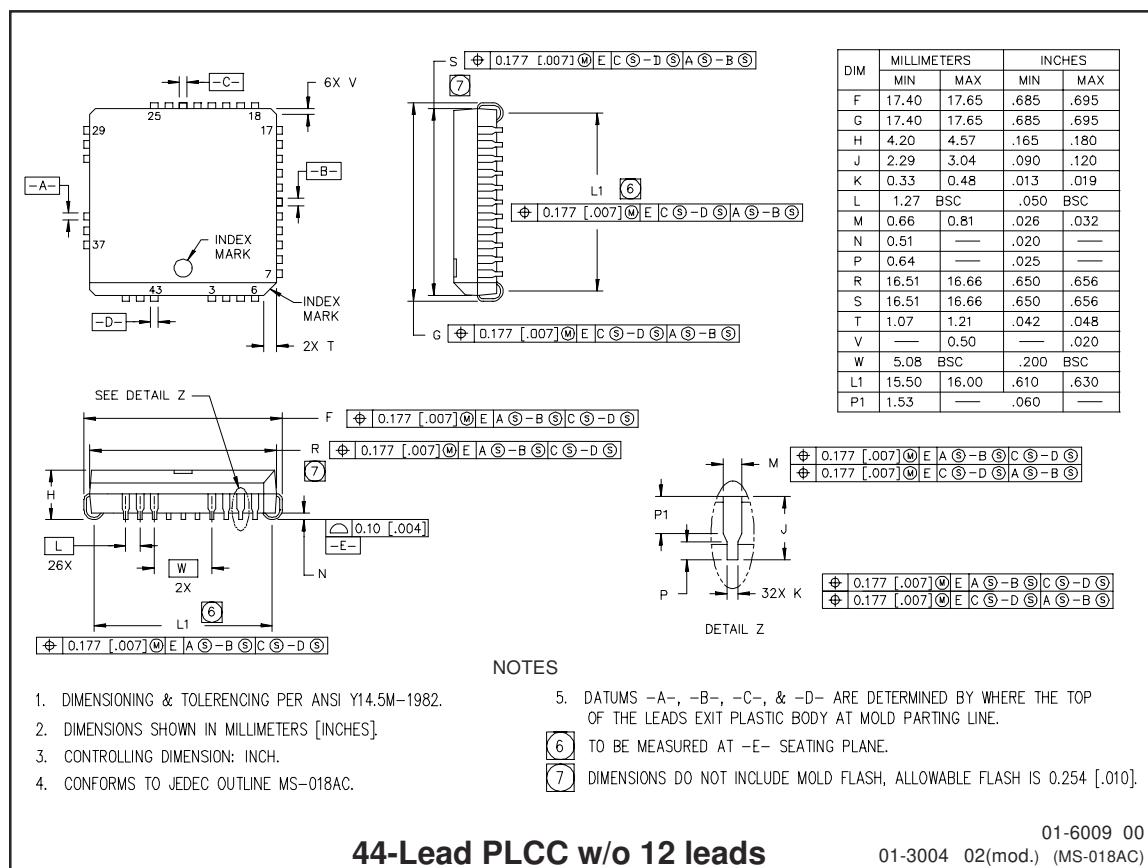
Case outlines



28-Lead PDIP (wide body)



28-Lead SOIC (wide body)



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